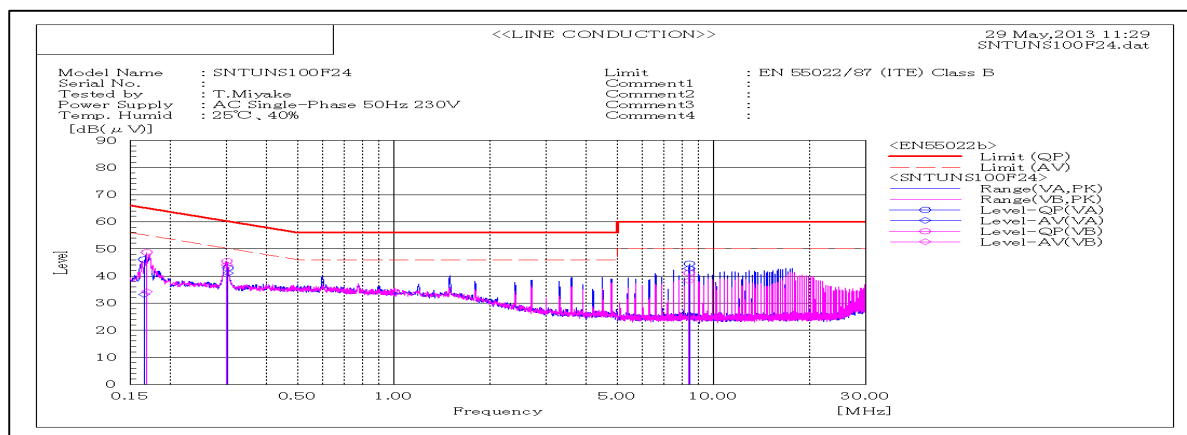
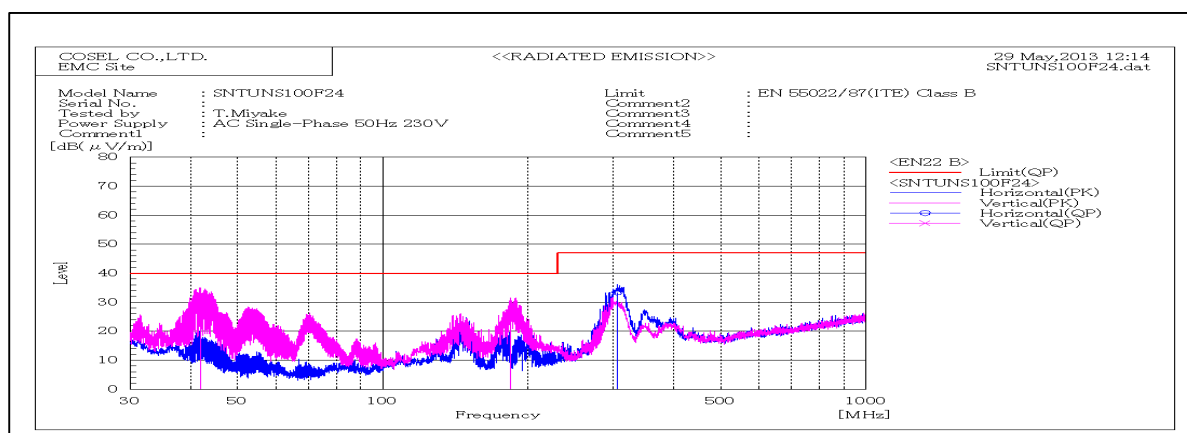


# DATA SHEET

		Date	19-Jul-13
Model	SNTUNS100F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.16548	VA	25.9	13	20.2	46.1	33.2	65.2	55.2	19.1	22	Pass	
0.16887	VB	28.6	14.1	20.2	48.8	34.3	65	55	16.2	20.7	Pass	
0.3008	VB	25.3	24	20.1	45.4	44.1	60.2	50.2	14.8	6.1	Pass	
0.30291	VA	22.8	21	20.1	42.9	41.1	60.2	50.2	17.3	9.1	Pass	
8.39517	VB	20.4	17.5	20.7	41.1	38.2	60	50	18.9	11.8	Pass	
8.39759	VA	23.7	22	20.8	44.5	42.8	60	50	15.5	7.2	Pass	

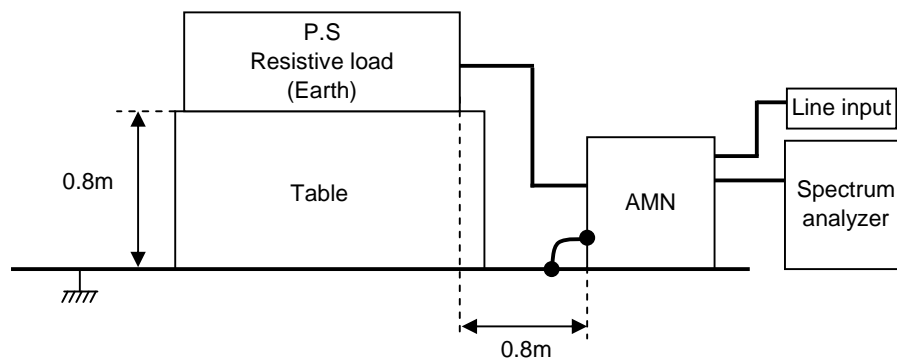


Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
41.995	V	Stable	48.1	-16.2	31.9	40	8.1	Pass	121	220	
183.862	V	Stable	42.1	-16	26.1	40	13.9	Pass	100	276	
305.261	H	Stable	51	-17.6	33.4	47	13.6	Pass	103	250	

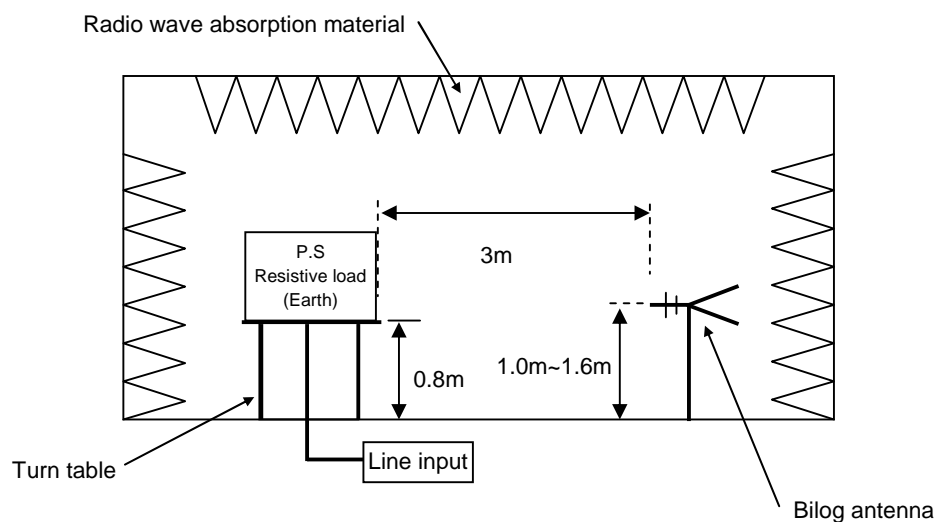


DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission





Test:EMI

Model Name: SNTUNS100F Series

○ Photographs of Test Set-Up

## LINE CONDUCTION

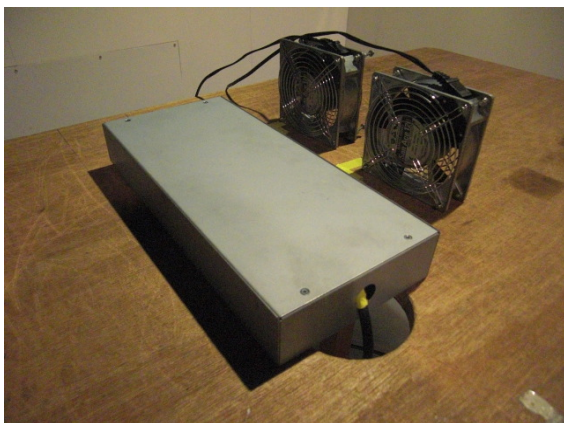


(A) Outside of a case

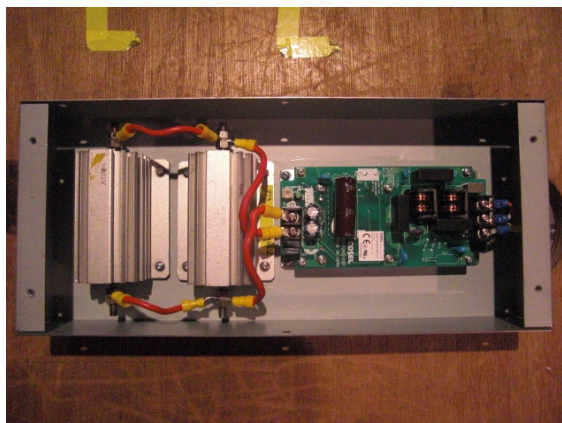


(B) Inside of a case

## RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case